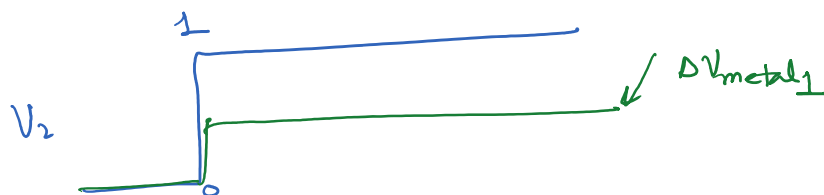
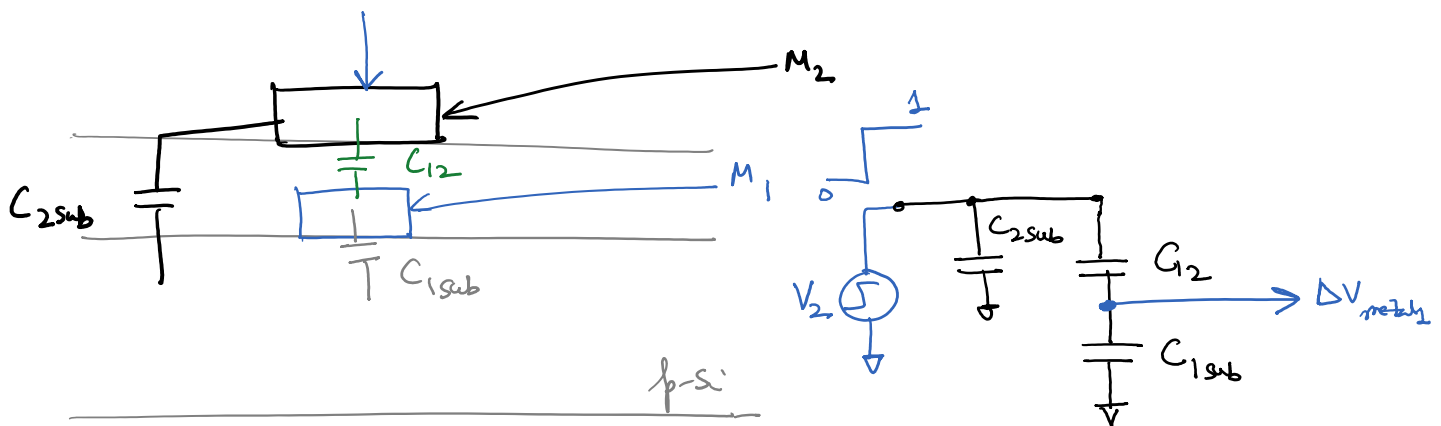
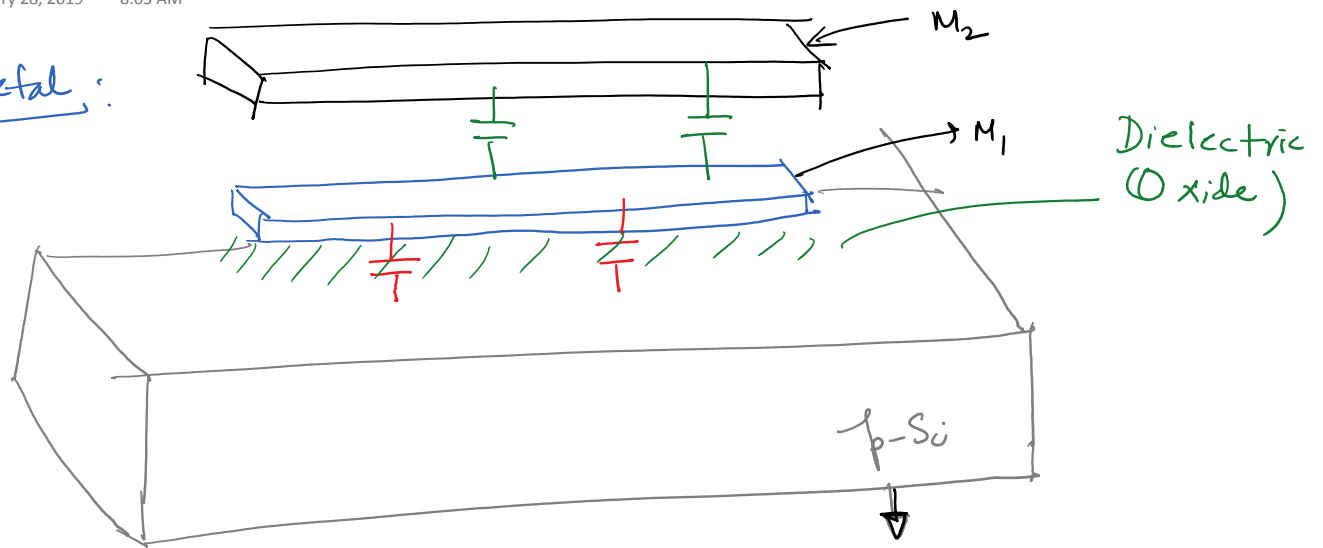


# ECF 445 - Lecture 5.

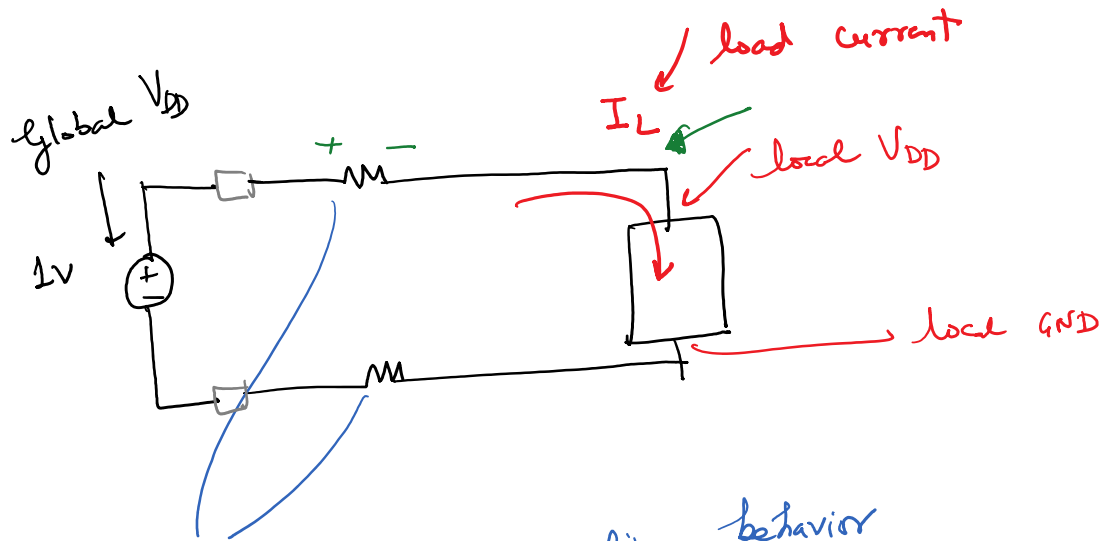
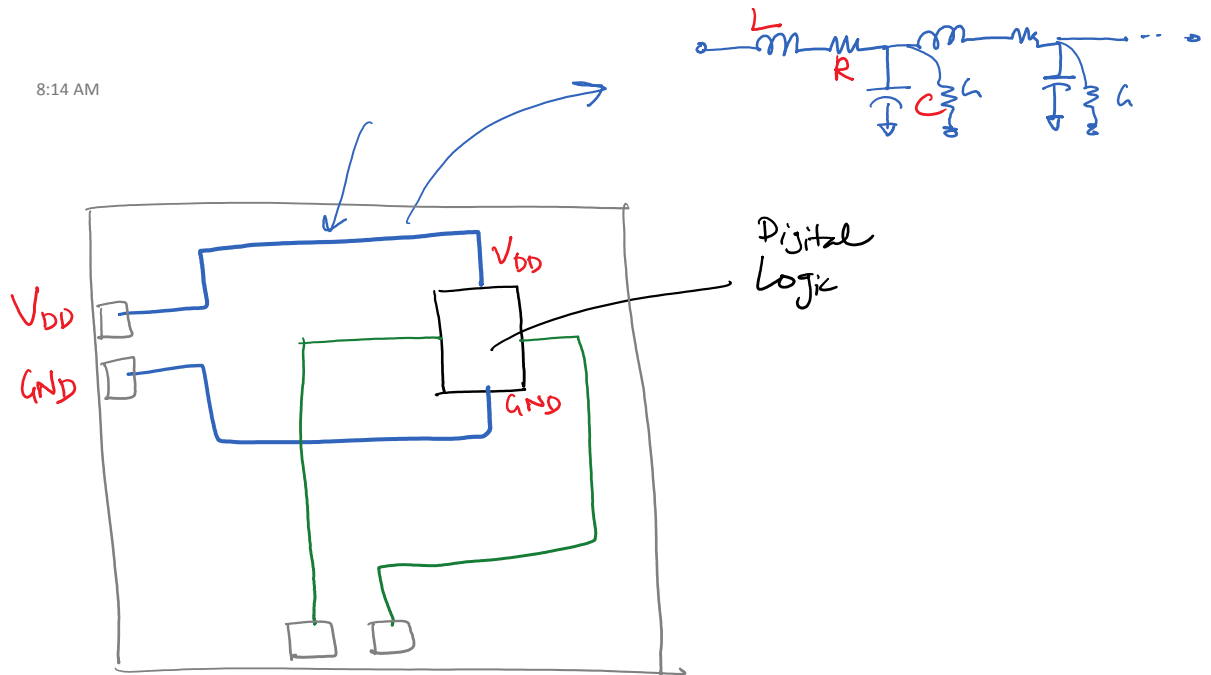
Monday, January 28, 2019 8:03 AM

Metal:



\* Cross coupling  $\approx$  Crosstalk due to Metal-metal

Capacitance.



⇒ Assume RC transmission line behavior

$$L = 10 \text{ mm}$$

$$W = 150 \text{ nm} = 0.15 \mu\text{m}$$

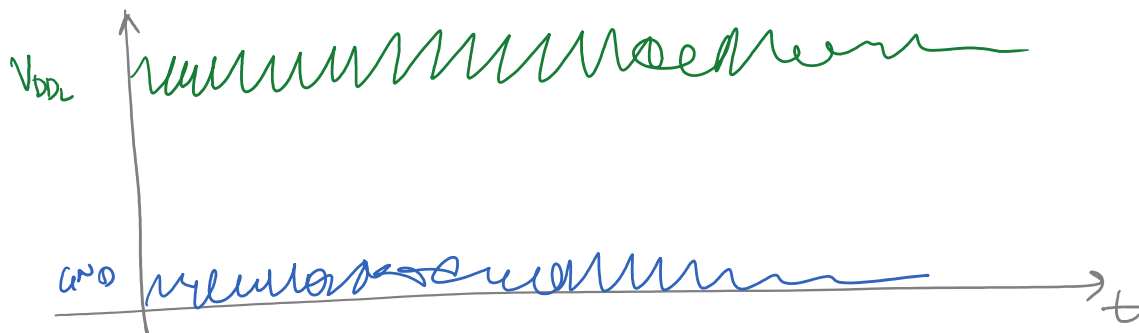
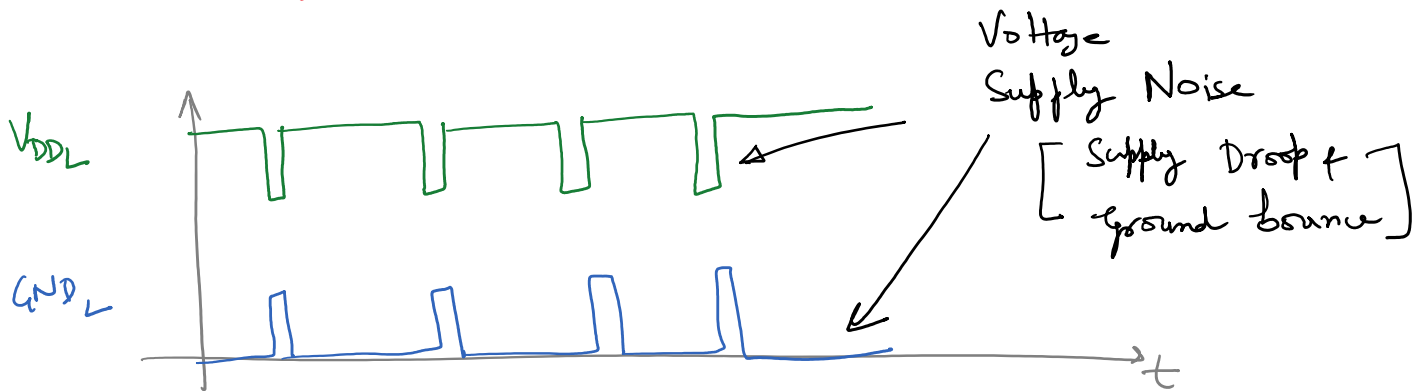
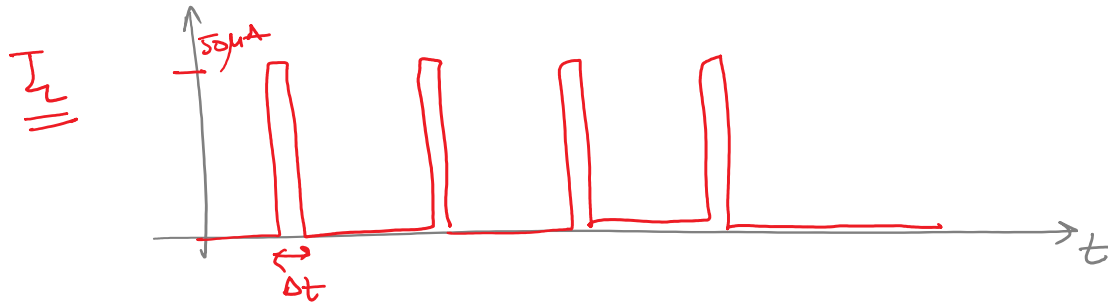
$$R_0 = 0.1 \frac{\Omega}{\mu\text{m}}$$

$$R_w = 0.1 \times \frac{10 \times 10^{-3}}{150 \times 10^{-9}} = 6.67 \text{ k}\Omega$$

DC:  $I_L = 50 \mu A$

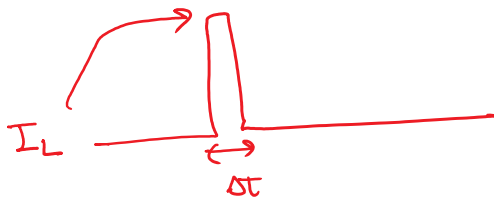
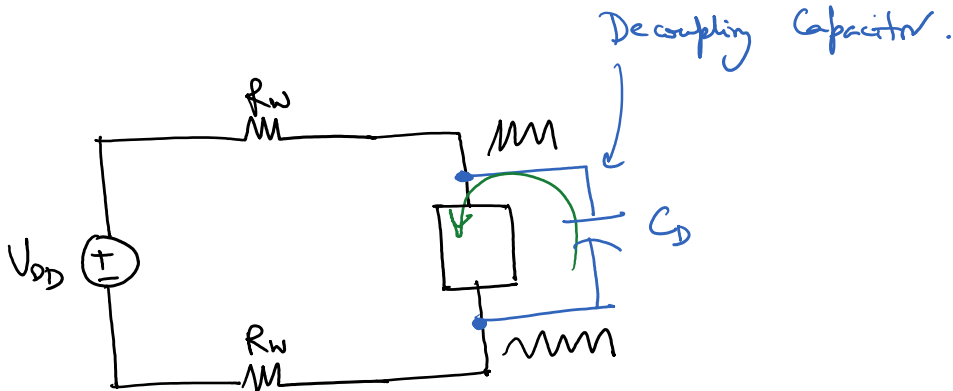
local  $V_{DD} = V_{DD,L} = V_{DD} - I_L \cdot R_W = 667 mV$

local  $GND = GND_L = 0 + I_L \cdot R_W = 333 mV$



ASICs  $\Rightarrow$  Power & Signal Integrity Tools

# Decoupling Capacitors



Assuming that the instantaneous charge  $\Delta Q = I_L \cdot \Delta t$  is entirely provided by the cap  $C_D$

$\Rightarrow$



$$\Delta Q = I_L \cdot \Delta t = C_D \cdot \Delta V$$

$$\Rightarrow \Delta V = \frac{I_L \cdot \Delta t}{C_D}$$

ripple in the supply voltage between local  $V_{DD}$  &  $V_{DD}$ .

Ex.  $I_L = 50 \mu A$ ,  $\Delta t = 10 ns$

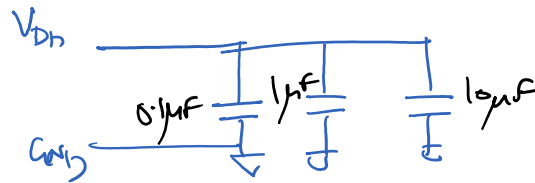
$$\Delta V \leq 10 mV$$

$$\Rightarrow C_0 > \frac{I_L \cdot \Delta t}{\Delta V} = \underline{\underline{50 \text{ pF}}}$$

typically  $\approx \underline{\underline{1 \text{ pF}}}$

"MOSCAP"

x High-Speed Digital Design: A book by Black Majik



Surface Mount

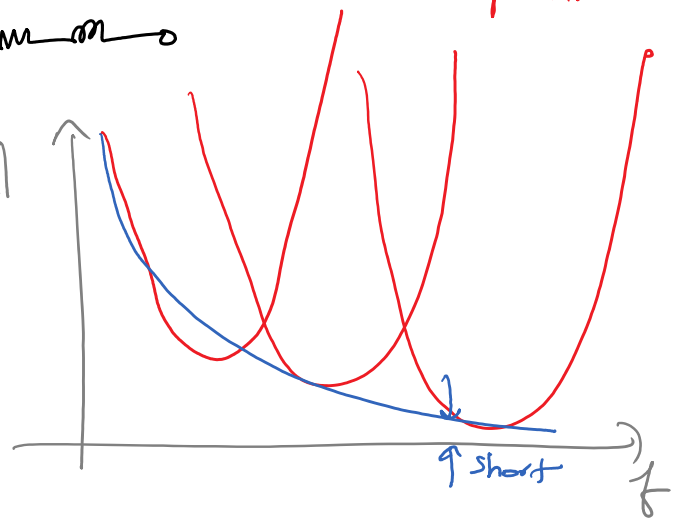


$$Z = \frac{1}{j\omega C}$$



$|X_L|$

Capacitor Bank



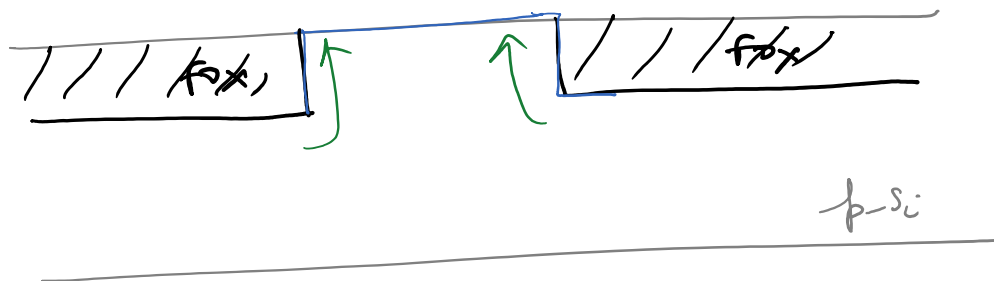
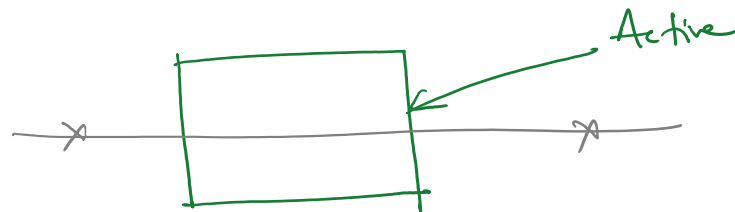
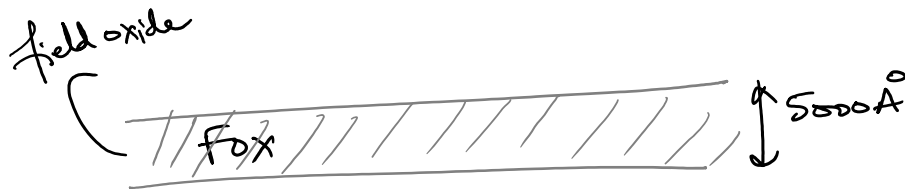
Rule of thumb  $\Rightarrow$

$< 1 \mu$  impedance with the capacitor at the frequencies of interest for decoupling.

# Chapter 4: Active Layers

n-well  
M1, M2, M3. ---  
Via 1, 2  
glass

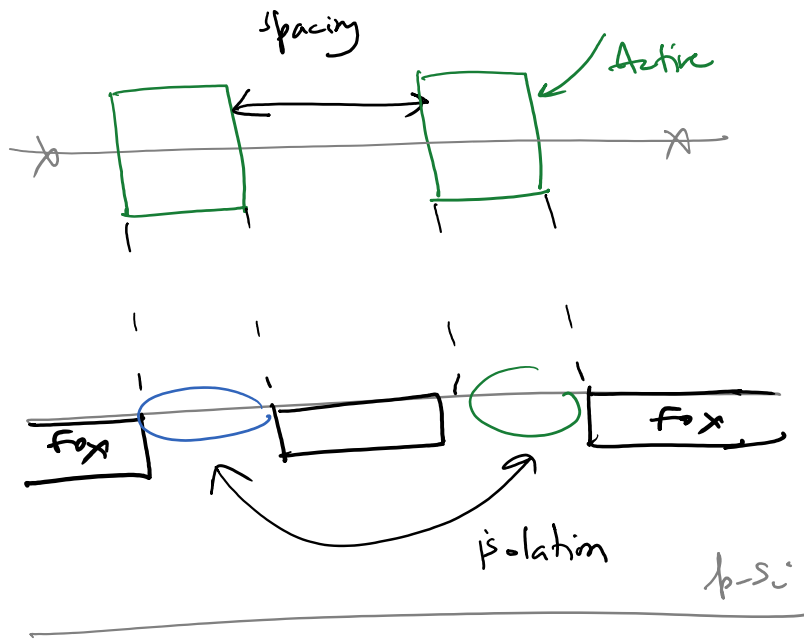
"Active layer"



\* Active layer opens a region in the field oxide  
↳ where all transistors are created.

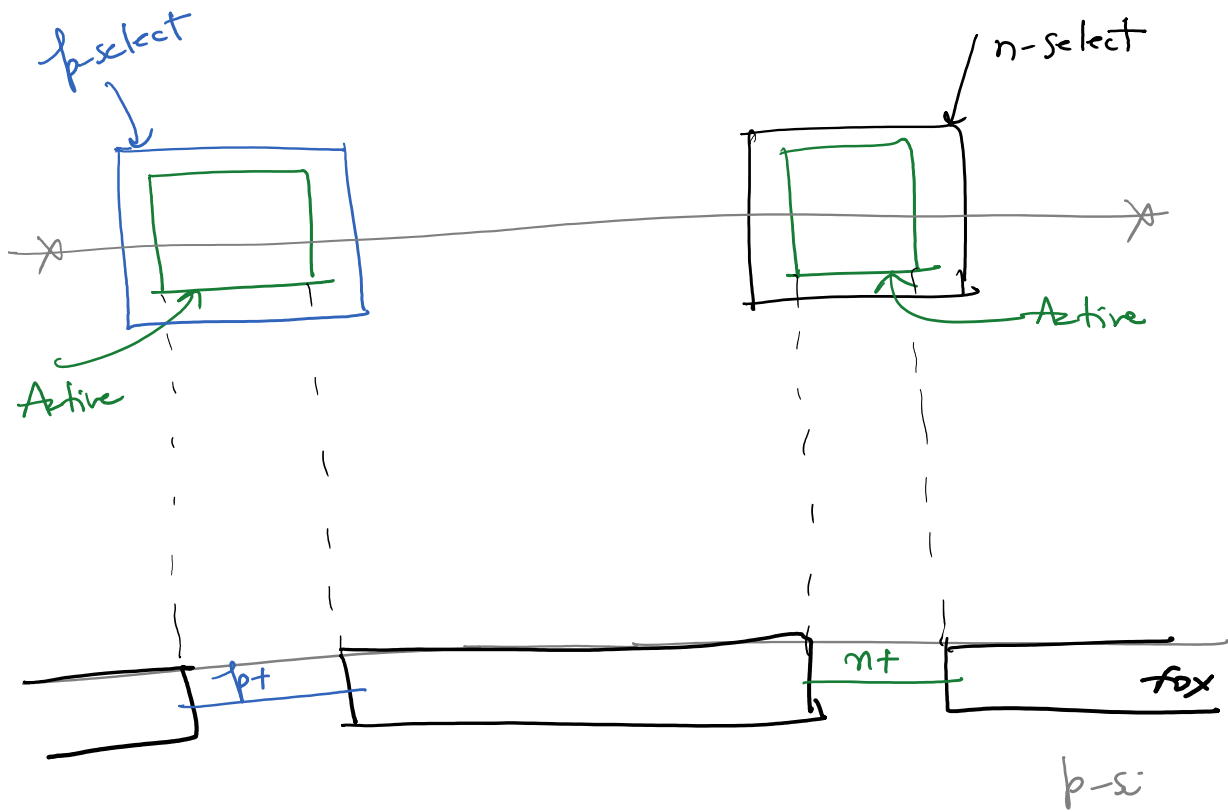
\* FOX is used to isolate devices from one another

↳ thick enough to keep interaction of adjacent areas to a minimum.

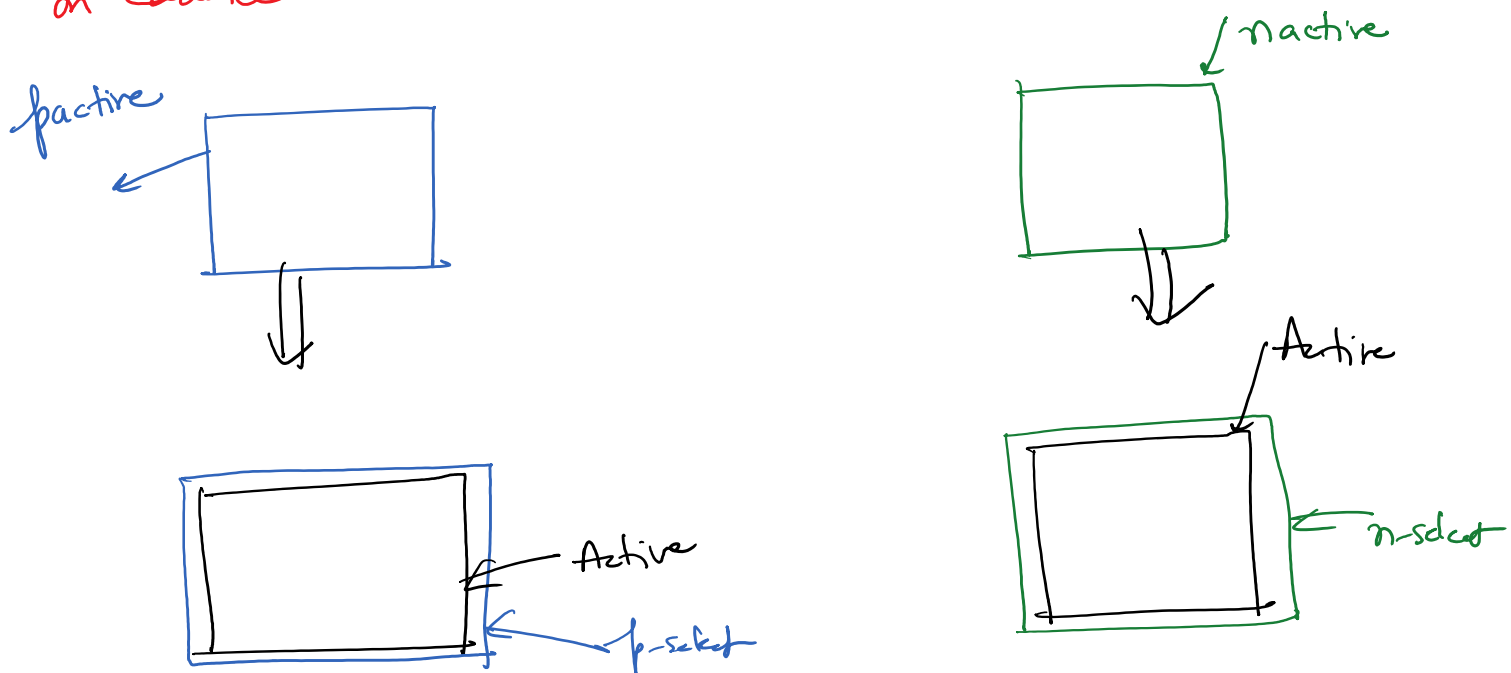


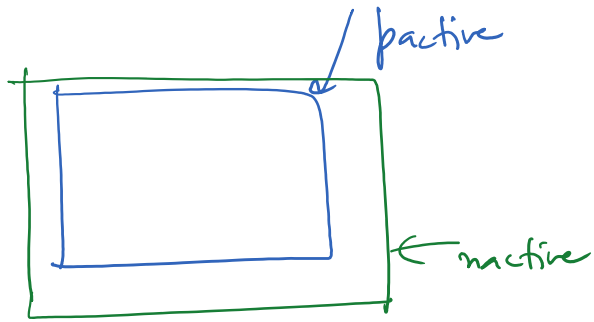


p and n select layers :

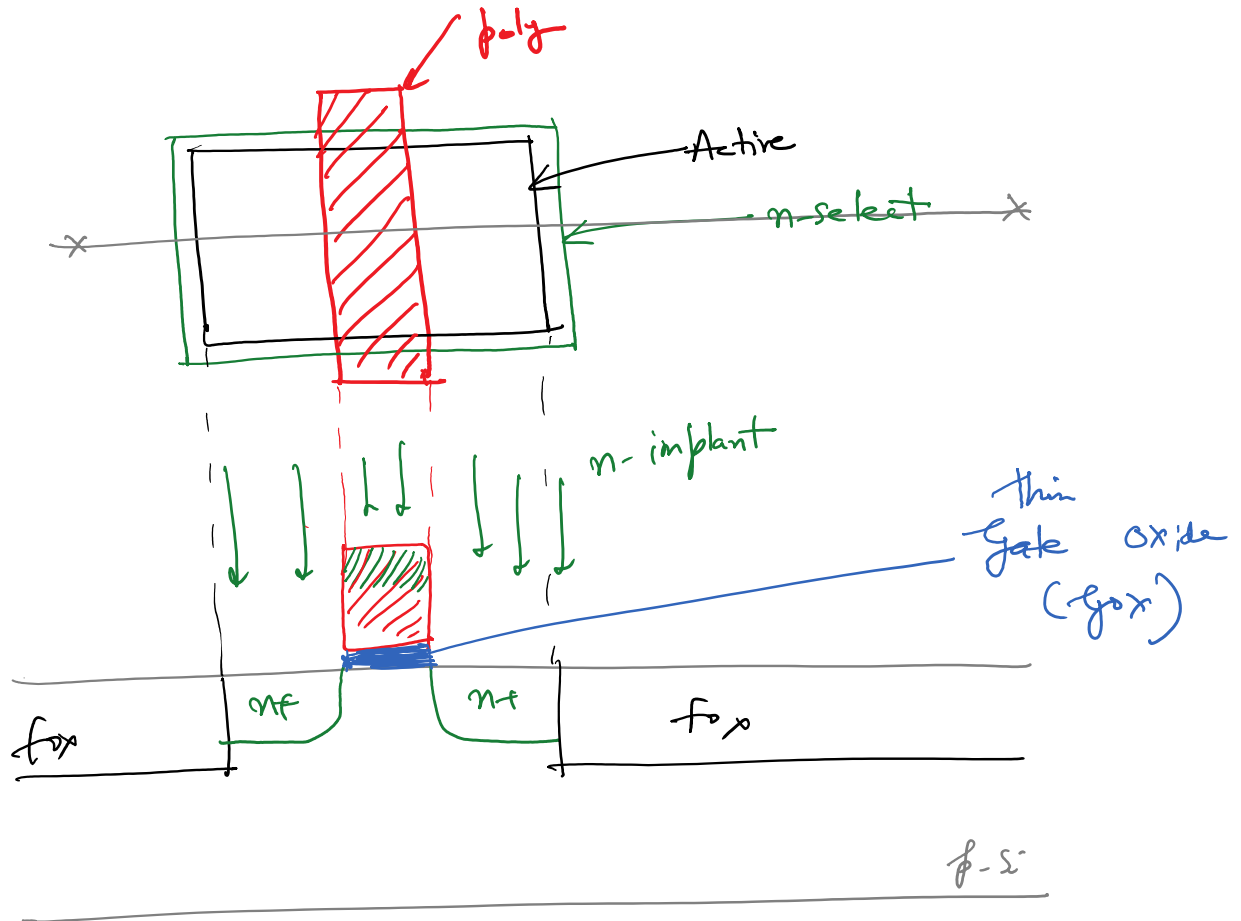


In Cadence





Poly Layer: polysilicon layer is used for MOSFET formation  
 ↳ "poly" acts as a "mask" for the drain/source implants.

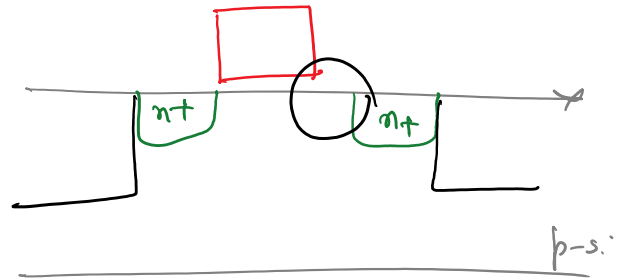
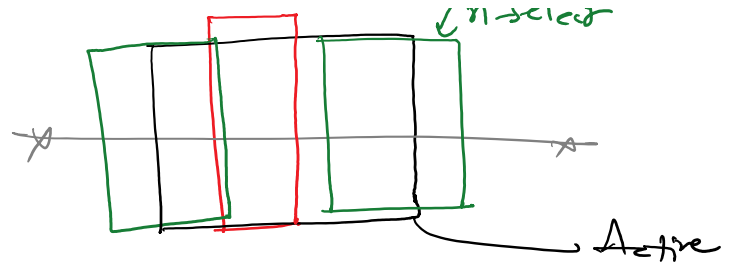
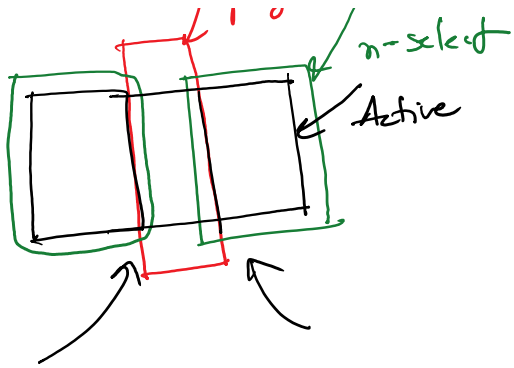


\* Self-aligned gate process.

→ poly over Active  $\Rightarrow$  MOSFET

Problem Layout





## \* Mask Misalignments

- ↳ poly overlap of source-drain region is not controllable
- ↳ Self-aligned gate is used by default.

poly.



\* poly can be used like a wire for routing.

↳ poly and active regions are "Silicided" by default.

Silicide  $\Rightarrow$  Cobalt or Tungsten  
+ Silicon/polysilicon